

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	273	(switchboard same circuit\$1 same breaker)	USPAT; JPO	OR	OFF	2006/06/21 13:10

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	120	(switchboard same circuit\$1 same breaker).ab.	USPAT; JPO	OR	OFF	2006/06/21 13:09
L3	273	(switchboard same circuit\$1 same breaker)	USPAT; JPO	OR	OFF	2006/06/21 13:10
S1	1	"2002134025"	USPAT; JPO	OR	OFF	2006/03/31 09:54
S2	12	KOGURE near TOSHIHIKO	USPAT; JPO	OR	OFF	2006/03/17 09:24
S3	0	KOGURE near TOSHIHIKO	USPAT	OR	OFF	2006/03/17 09:24
S4	9	KOGURE and TOSHIHIKO	USPAT	OR	OFF	2006/03/17 09:24
S5	15	"5468752"	USPAT; JPO	OR	OFF	2006/03/17 09:25
S6	1	"2003243855"	USPAT; JPO	OR	OFF	2006/03/17 09:25
S7	7	"2953039"	USPAT; JPO	OR	OFF	2006/03/17 09:26
S8	26	IKURA near TSUNEO	USPAT; JPO	OR	OFF	2006/03/17 09:28
S9	43	WAKITANI near TAKAO	USPAT; JPO	OR	OFF	2006/03/17 09:30
S10	88	OTANI same TOSHIYA	USPAT; JPO	OR	OFF	2006/03/17 09:31
S11	88	OTANI near TOSHIYA	USPAT; JPO	OR	OFF	2006/03/17 09:31
S12	23	S11 and light\$3	USPAT; JPO	OR	OFF	2006/03/17 09:31
S13	6	(light\$3 same inspection same display same panel\$1).clm.	USPAT; JPO	OR	OFF	2006/03/17 09:40
S14	6	(light\$3 same inspection same display\$1 same panel\$1).clm.	USPAT; JPO	OR	OFF	2006/03/17 09:40
S15	170	(light\$3 same inspection same display\$1 same panel\$1).ab.	USPAT; JPO	OR	OFF	2006/03/17 09:40
S16	2	S15 and chassis	USPAT; JPO	OR	OFF	2006/03/17 09:40
S17	7	"6058235"	USPAT; JPO	OR	OFF	2006/03/31 09:57
S18	1	(usb and test and microprocessor).ab.	USPAT; JPO	OR	OFF	2006/03/31 10:00
S19	3	(usb\$1 and test\$3 and microprocessor\$1).ab.	USPAT; JPO	OR	OFF	2006/03/31 10:07

EAST Search History

S20	3	(usb and test\$3 and microprocessor\$1).ab.	USPAT; JPO	OR	OFF	2006/03/31 10:08
S21	568	(usb and host).ab.	USPAT; JPO	OR	OFF	2006/03/31 10:08
S22	14	(usb and host and test\$3).ab.	USPAT; JPO	OR	OFF	2006/03/31 10:53
S23	4	"6480801"	USPAT; JPO	OR	OFF	2006/03/31 10:17
S24	778	(semiconductor\$1 same devices same carrier same manufacturing)	USPAT; JPO	OR	OFF	2006/03/31 10:54
S25	20	(semiconductor\$1 same devices same carrier same manufacturing same test\$3 same packag\$3)	USPAT; JPO	OR	OFF	2006/03/31 12:42
S26	25025	(isolation near\$ buffer\$1 same test\$3 same bypass).clm.	USPAT; JPO	OR	OFF	2006/03/31 12:43
S27	25019	(isolation near\$ buffer\$1 same test\$3 same bypass same channel\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 12:43
S28	0	(isolation near buffer\$1 same test\$3 same bypass same channel\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 12:44
S29	0	(isolation near buffer\$1 same test\$3 same bypass).clm.	USPAT; JPO	OR	OFF	2006/03/31 12:44
S30	3	(isolation near buffer\$1 same test\$3).clm.	USPAT; JPO	OR	OFF	2006/03/31 12:45
S31	0	(isolation near buffer\$1 same test\$3 same bypass)	USPAT; JPO	OR	OFF	2006/03/31 12:45
S32	0	(isolation near buffer\$1 same test\$3 same bypass)	USPAT; JPO	OR	OFF	2006/03/31 12:46
S33	4	(isolation near buffer\$1 same test\$3 same channel\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:46
S34	275	(buffer\$3 same bypass same test\$3)	USPAT; JPO	OR	OFF	2006/03/31 12:50
S35	67	S34 and isolation\$3	USPAT; JPO	OR	OFF	2006/03/31 12:48
S36	0	S35 and (test\$3 near channel\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:47
S37	1932	MILLER near CHARLES	USPAT; JPO	OR	OFF	2006/03/31 12:48
S38	200131	MILLER adj CHARLES	USPAT; JPO	OR	OFF	2006/03/31 12:48
S39	1857	MILLER adj CHARLES	USPAT; JPO	OR	OFF	2006/03/31 12:48

EAST Search History

S40	0	CHARLES adj millers	USPAT; JPO	OR	OFF	2006/03/31 12:49
S41	77	CHARLES adj miller	USPAT; JPO	OR	OFF	2006/03/31 12:48
S42	77	CHARLES adj miller	USPAT; JPO	OR	OFF	2006/03/31 12:48
S43	4	S42 and buffer	USPAT; JPO	OR	OFF	2006/03/31 12:50
S44	77	charles adj miller	USPAT; JPO	OR	OFF	2006/03/31 12:49
S45	4	S44 and buffer	USPAT; JPO	OR	OFF	2006/03/31 12:50
S46	20	S34 and miller	USPAT; JPO	OR	OFF	2006/03/31 12:52
S47	30	(isolation adj buffer\$1) and (delay near circuit\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:55
S48	0	(remotely and buffer\$3 and channel\$1).ti.	USPAT; JPO	OR	OFF	2006/03/31 12:55
S49	105	(buffer\$3 and channel\$1).ti.	USPAT; JPO	OR	OFF	2006/03/31 12:57
S50	0	S49 and (isolat\$3 near buffer\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:57
S51	0	S49 and (isolat\$4 near buffer\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:58
S52	3	S49 and (delay near circuit\$1)	USPAT; JPO	OR	OFF	2006/03/31 12:59
S53	262	HILL adj GREGORY	USPAT; JPO	OR	OFF	2006/03/31 13:00
S54	2	GREGORY adj hill	USPAT; JPO	OR	OFF	2006/03/31 13:00
S55	0	S53 and dielectric	USPAT; JPO	OR	OFF	2006/03/31 13:01
S56	0	(circuit\$1 same test\$3 same dielectri same contactor).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:02
S57	0	(circuit\$1 same test\$3 same dielectrid same contactor).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:02
S58	0	(circuit\$1 same test\$3 same dielectric same contactor).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:02
S59	138	(circuit\$1 same test\$3 same dielectric).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:02
S60	0	S59 and load near board\$1	USPAT; JPO	OR	OFF	2006/03/31 13:02
S61	2	S59 and load\$3 near board\$1	USPAT; JPO	OR	OFF	2006/03/31 13:04

EAST Search History

S62	0	(dielectric and load and board\$1).ti.	USPAT; JPO	OR	OFF	2006/03/31 13:04
S63	0	(dielectric and test\$3 and mat\$3).ti.	USPAT; JPO	OR	OFF	2006/03/31 13:04
S64	25	(dielectric and mat\$3).ti.	USPAT; JPO	OR	OFF	2006/03/31 13:36
S65	3	"6,788,086"	USPAT; JPO	OR	OFF	2006/03/31 13:38
S66	12238	(first and second and stress).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:39
S67	124	(first and second and stress and directional\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:39
S68	0	(first and second and stress and directional\$1 and semiconductor\$1 and probe\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 13:39
S69	1	(first and second and stress and directional\$1 and probe\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 14:17
S70	1	(isolation near buffer\$1) and (bypass near buffer\$1)	USPAT; JPO	OR	OFF	2006/03/31 14:20
S71	1	(calibrat\$3 and voltage and sensor\$1 and breaker\$1 and bus and circuit\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 14:22
S72	0	(calibrat\$3 same voltage same sensor\$1 same breaker\$1 and circuit\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 14:23
S73	4	(sensor and switchboard and breaker).ab.	USPAT; JPO	OR	OFF	2006/03/31 14:24
S74	3	(sensor same switchboard same circuit\$1 same breaker)	USPAT; JPO	OR	OFF	2006/03/31 14:34
S75	120	(switchboard same circuit\$1 same breaker).ab.	USPAT; JPO	OR	OFF	2006/06/21 13:10
S76	24	(switchboard same circuit\$1 same breaker and bus).ab.	USPAT; JPO	OR	OFF	2006/03/31 14:37
S77	10003	(circuit and breaker).ti.	USPAT; JPO	OR	OFF	2006/03/31 14:37
S78	30	S77 and S75	USPAT; JPO	OR	OFF	2006/03/31 14:38
S79	1	(voltage near sensor and switchboard\$1).ab.	USPAT; JPO	OR	OFF	2006/03/31 14:40
S80	1	(voltage near sensor and switchboard\$1).clm.	USPAT; JPO	OR	OFF	2006/03/31 14:50
S81	535	324/74	USPAT; JPO	OR	OFF	2006/03/31 17:28

EAST Search History

S82	535	324/74	USPAT; JPO	OR	OFF	2006/03/31 17:36
S83	2	S82 and switchboard\$1	USPAT; JPO	OR	OFF	2006/03/31 17:29
S84	17	324/142 and switchboard\$1	USPAT; JPO	OR	OFF	2006/03/31 17:51
S85	5	324/157 and switchboard\$1	USPAT; JPO	OR	OFF	2006/03/31 17:53
S86	6	361/659 and switchboard\$1	USPAT; JPO	OR	OFF	2006/03/31 17:53
S87	5	361/681 and switchboard\$1	USPAT; JPO	OR	OFF	2006/06/21 13:09

Nguyen, Trung Q

From: PLUS
Sent: Wednesday, June 21, 2006 4:01 PM
To: Nguyen, Trung Q
Subject: PLUS Results for 10500364

Here are the PLUS search results for 10500364.

This search was prepared by the staff of the Scientific and Technical Information Center, SIRA. If you have questions or comments about this search, please reply via email to PLUS@uspto.gov.



10500364_QUAL.tx
t



10500364_LIST.txt



10500364_WEST.tx
t



10500364_EAST.tx
t



10500364.east



10500364_CLS.txt



10500364_CLSTITL10500364_WDS.txt
ES.txt